



Docket No.: GR 00 P 1679

O / ID# 2858
E. Willis
9 - 20 - 01

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By: D. P. T.

Date: 9/12/01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Dieter Kantz et al.
Applic. No. : 09/826,594
Filed : April 5, 2001
Title : Test Configuration for the Functional Testing of a Semiconductor Chip
Art Unit : 2858

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INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,
Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

United States Patent No. 5,241,266 (Ahmad et al.), dated August 31, 1993;

Prof. Dr. Claus Reuber: "Laserstrahl statt Prüfspitze" [laser beam instead of probe point], Elektronik, No. 24, 1997, pp. 96-102.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications,

patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,



For Applicants

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Date: September 12, 2001

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